P.E.S. College of Engineering, Mandya - 571 401 (An Autonomous Institution affiliated to VTU, Belagavi) Second Semester, M. Tech - VLSI Design and Embedded System (MECE) Semester End Examination; May/June - 2018 Design of VLSI System Time: 3 hrs Max. Marks: 100 Note: Answer FIVE full questions, selecting ONE full question from each unit.			
UNIT - I 1 a. Explain in detail of structured design techniques.	10		
b. Explain the terms:	10		
i) Programmable logic devices	10		
ii) Programmable inter connect	10		
2 a. Explain the concept of hierarchy in VLSI design.	5		
b. Write a short note on full custom design.	5		
c. Briefly explain the EDA tools for system.	10		
UNIT - II			
3 a. Explain the following design capture tools:			
i) HDL design	10		
ii) Schematic design			
b. Discuss different types of simulation tools used in verification of VLSI system.	10		
4 a. With necessary arrangements, explain the chip composition high-lighting the progression of	5		
steps at each level.	5		
b. Explain the terms:			
i) Time Verifiers	15		
ii) Network isomorphism	10		
iii) Netlist comparision			
UNIT - III			
5 a. Draw the schematic diagram of a comparator to compare the magnitude of two 4-bit binary	10		
number using adders. Explain the operation for unsigned and signed comparison.			
b. Design a 16-bit carry select adder using 4-bit adder, in each group write expression for critical path delay.	10		
6 a. With an example show how the multiplication is performed using radix-4 booth encoding.	10		
Explain in brief.	I		
b. Draw the basic ROM architecture using programmable ROM and NAND ROM and explain its working.	10		

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UNIT - IV

7 a.	Explain the FSM design procedure with an example.	10	
b.	Discuss the power distribution employed while designing special purpose subsystem.	10	
8 a.	Explain the global clocking strategies in modern VLSI design of PLL.	10	
b.	With a neat diagram, explain the working of CMOS inverter as an amplifier.	10	
UNIT - V			
9 a.	Explain in detail about fault models.	5	
b.	Explain how serial and parallel scan testing is implemented.	5	
c.	Explain the terms :		
	i) Recurring cost	10	
	ii) Non-currring cost		
10 a.	Explain in brief, boundary scan techniques.	10	
b.	Discuss different types of fault models in VLSI design.	10	

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